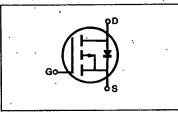
### 7964142 SAMSUNG SEMICONDUCTOR IRF9130/9131/9132/9133 IRFP9130/9131/9132/9133 IRF9530/9531/9532/9533

**Preliminary Specifications** 

#### -100 Volt, 0.30 Ohm SFET



#### FEATURES

- . Low RDS(on) Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Low input capacitance ٠
- Extended safe operating area
  Improved high temperature reliability

## POWER MOSFE<u>T</u>S

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#### PRODUCT SUMMARY

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Part Number	VDS	R <sub>DS(on)</sub>	ΊD
IRF/IRFP9130, IRF9530	-100V	0.30 <b>Ω</b>	-12A
IRF/IRFP9131, [RF9531	-60V	0.300	-12A
IRF/IRFP9132, IRF9532	-100V	0.40 <b>Ω</b>	-10A
IRF/IRFP9133, IRF9533	-60V	0.40 <b>Ω</b>	-10A

#### PACKAGE STYLE

Package Type	Part Number
TO-3	IRF9130/9131/9132/9133
TO-3P	IRFP9130/9131/9132/9133
. TO-220	IRF9530/9531/9532/9533

#### **MAXIMUM RATINGS**

Characteristic	Symbol	9130 9530	9131 9531	9132 9532	9133 9533	Unit
Drain-Source Voltage (1)	VDSS	-100	-60	-100	-60	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0M <sup>D</sup> ) (1)	VDGR	-100	60	<del>~</del> 100	-60	Vdc
Gate-Source Voltage	V <sub>GS</sub>		±	20		Vdc
Continuous Drain Current T <sub>C</sub> =25°C	lo	-12	-12	-10	-10	Adc
Continuous Drain Current T <sub>C</sub> =100°C	ło	-7.5	-7.5	-6.5	-6.5	Adc
Drain Current-Pulsed (3)	IDM	-48	-48	-40	-40	Adc
Gate Current—Pulsed	IGM		±	1.5	-	Adc
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	PD		75 0.6			
Operating and Storage Junction Temperature Rangy	Tյ, Tstg	-55 to 150				°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL		3	00		°C

Notes: (1) TJ=25°C to 150°C

(2) Pulse test: Pulse width≤300µs, Duty Cycle≤2%
(3) Repetitive rating: Pulse width limited by max. junction temperature

SAMSUNG SEMICONDUCTOR

#### 7964142 SAMSUNG SEMICONDUCTOR INC IRF9130/9131/9132/9133 IRFP9130/9131/9132/9133 IRF9530/9531/9532/0522

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ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise specified)

Characteristic	Symbol	Туре	Min	Тур	Max	Units	Test Conditions
Drain-Source Breakdown	BVDSS	IRF9130/2 IRFP9130/2 IRF9530/2	-100	-	-	v	V <sub>GS</sub> =0V
Voltage	DVDSS	IRF9131/3 IRF99131/3 IRF9531/3	-60	-	-	v	I <sub>D</sub> =-250μA
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	-2.0	1	-4.0	V	$V_{DS}=V_{GS}, I_D=-250\mu A$
Gate-Source Leakage Forward	lass	ALL	I	I	-100	пΑ	V <sub>GS</sub> ≕-20V
Gate-Source Leakage Reverse	lass	ALL	1	1	100	nA	V <sub>GS</sub> =20V
Zero Gate Voltage	Ipss	·ALL	1		-250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
Drain Current	1088		1	-	-1000	μA	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C
On-State Drain-Source	ID(on)	IRF9130/1 IRF99130/1 IRF9530/1	-12	I	-	Α.	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , V <sub>GS</sub> =-10V
Current (2)	U(ON)	IRF9132/3 RFP9132/3 IRF9532/3	-10	-	-	. <b>A</b>	VUS/ULION/AVUSION/ max., VUS- 10V
Static Drain-Source On-State	R <sub>DS(on)</sub>	IRF9130/2 IRFP9132/2 IRF9530/2	-	-	0.30	۵	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.5A
Resistance (2)	* US(on)	IRF9131/3 IRFP9131/3 IRF9531/3	-	-	0.40	Ω	VGS 10, 10 0.0A
Forward Transconductance (2)	Qfs	ALL	2.0	-	-	8	V <sub>DS</sub> >i <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , I <sub>D</sub> =-6.5A
Input Capacitance	Ciss	ALL	-	_	700	pF	
Output Capacitance	Coss	ALL	_	-	450	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, f=1.0MHz
Reverse Transfer Capacitance	Crss	ALL	-	_	200	рF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	-	_	60	ns	
Rise Time	Tr	ALL.	I	1	140	ns	$V_{DD}=0.5BV_{DSS}$ , $l_D=-6.5A$ , $Z_O=50\Omega$ (MOSFET switching times are essentially
Turn-Off Delay Time	t <sub>d(off)</sub>	ALL	_	_	140	ns	independent of operating temperature.)
Fall Time	tí	ALL	-		140	ns	
Total Gate Charge (Gate-Source Plus Gate-Drain)	Qg	ALL	-	-	45	nC	$V_{GS} = -15V, I_D = -15A, V_{DS} = 0.8$ Max.
Gate-Source Charge	Q <sub>gs</sub>	ALL	-	-	20	nC	Rating (Gate charge is essentially independent of operating temperature.)
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	ALL	-	_	25	nC	

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P-CHANNEL

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POWER MOSFETS

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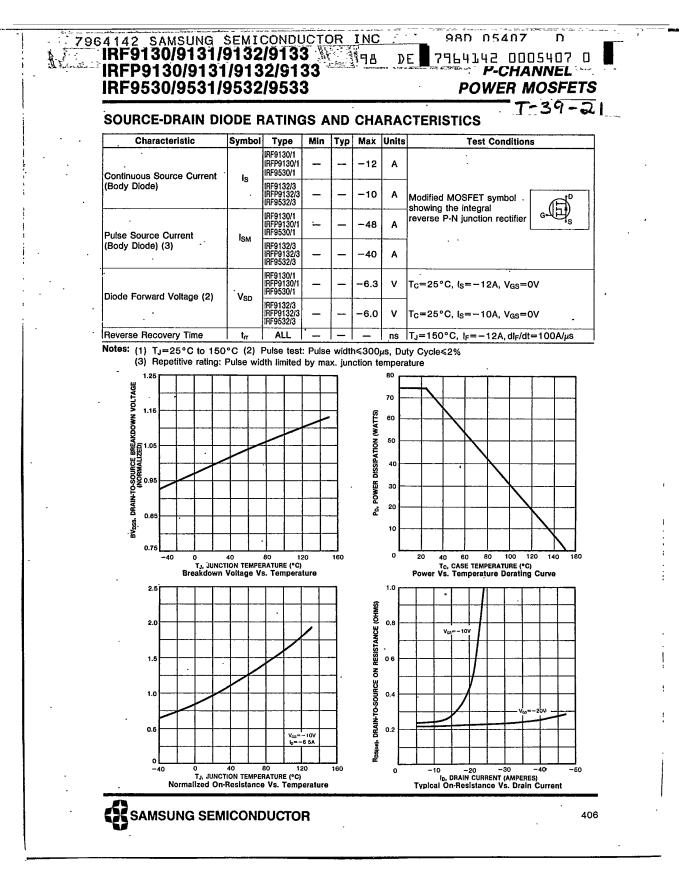
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#### THERMAL RESISTANCE

Junction-to-Case	RthJC	ALL	. —	-	1.67	к/w	
Case-to-Sink	RthCS	ALL	-	1.0	-	к/w	Mounting surface flat, smooth, and greased
Junction-to-Ambient	RthJA	IRFPXXXX IRF95XX	-	-	80	ĸ/w	Free Air Operation
		IRF91XX	_	-	30	K/W	· ·

Notes: (1) TJ=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature

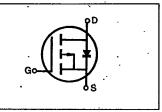
### SAMSUNG SEMICONDUCTOR



#### 7964142 SAMSUNG SEMICONDUCTOR INC 98 IRF9140/9141/9142/9143 IRFP9140/9141/9142/9143 IRF9540/9541/9542/9543

#### **Preliminary Specifications**

#### -100 Volt, 0.2 Ohm SFET



#### FEATURES

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- Low RDS(on)
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure ٠
- Low input capacitance ٠
- Extended safe operating area
- Improved high temperature reliability

#### **MAXIMUM RATINGS**

#### **PRODUCT SUMMARY**

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Part Number	VDS	R <sub>DS(on)</sub>	lo
IRF/IRFP9140, IRF9540	-100V	0.2 <i>S</i>	-19A
IRF/IRFP9141, IRF9541	-60V	0.2 បិ	-19A
IRF/IRFP9142, IRF9542	-100V	0.3 <b>û</b>	-15A
IRF/IRFP9143, IRF9543	-60V	0.3Ω	. <b>–</b> 15A

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**P-CHANNEL POWER MOSFETS** 

T-39-13

#### PACKAGE STYLE

Package Type	Part Number
то-з	IRF9140/9141/9142/9143
то-зр	IRFP9140/9141/9142/9143
TO-220	IRF9540/9541/9542/9543



Characteristic .	Symbol	9140 9540	9141 9541	9142 9542	9143 9543	Unit
Drain-Source Voltage (1)	VDSS	-100	<sup>.</sup> –60	-100	-60	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0MQ) (1)	VDGR	-100	-60	-100	-60	Vdc
Gate-Source Voltage	V <sub>GS</sub>		±	20		Vdc
Continuous Drain Current Tc=25°C	lo	-19	-19	-15	-15	Adc
Continuous Drain Current T <sub>C</sub> =100°C	lъ	-12	-12	-10	-10	Adc
Drain Current—Pulsed (3)	IDM	-76	-76	-60	-60	Adc
Gate Current-Pulsed	Ідм		±	1.5		Adc
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	PD	125 1.0				Watts W/°C
Operating and Storage Junction Temperature Range	T <sub>J</sub> , Tstg	-55 to 150			°C	
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	· TL	. 300				°C

 Notes: (1) TJ=25°C to 150°C

 (2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%

 (3) Repetitive rating: Pulse width limited by max. junction temperature



### 7964142 SAMSUNG SEMICONDUCTOR INC IRF9140/9141/9142/9143 IRFP9140/9141/9142/9143 IRF9540/9541/9542/9543

#### **P-CHANNE** POWER MOSFETS

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Characteristic	Symbol	Туре	Min	Тур	Max	Units	Test Conditions
Drain-Source Breakdown	BVDSS	IRF9140/2 IRF99140/2 IRF9540/2	-100			v	V <sub>GS</sub> =0V
/oltage	DVDSS	IRF9141/3 IRF99141/2 IRF9541/3	-60	-		v	I <sub>D</sub> =-250μA
Sate Threshold Voltage	VGS(th)	ALL	-2.0	1	-4.0	v	$V_{DS} = V_{GS}, I_D = -250\mu A$
Gate-Source Leakage Forward	lgss	ALL.	<u> </u>	1	-100	nA	V <sub>GS</sub> =-20V
Sate-Source Leakage Reverse	loss	ALL		<u> </u>	100	nA	V <sub>GS</sub> =20V
Zero Gate Voltage		ALL	-	—	-250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
Drain Current	loss	ALL	1	_	<b>∸</b> 1000	μA	$V_{DS}$ =Max. Rating×0.8, $V_{GS}$ =0V, $T_C$ =125°C
On-State Drain-Source		IRF9140/1 IRFP9140/1 IRF9540/1	<b>–</b> 19	<b>—</b> .	-	Α.	• V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(an)</sub> max., V <sub>GS</sub> =-10V
Current(2)	I <sub>D(оп)</sub>	IRF9142/3 IRFP9142/3 IRF9542/3	-15	-	-	A	
Static Drain-Source On-State	<b>B</b> -1	IRF9140/1 IRF99140/1 IRF9540/1	_	-	0.2	· 0	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A
Resistance (2)	R <sub>DS(on)</sub>	IRF9142/3 IRFP9142/3 IRF9542/3	-	-	0.3	۵	
Forward Transconductance (2)	<b>g</b> is	ALL	5.0		-		$V_{DS}>I_{D(on)}\times R_{DS(on) max.}$ , $I_{D}=-10A$
Input Capacitance	Ciss	ALL	- 1	·	1300	pF	· · ·
Output Capacitance	Coss	ALL	-	-	700	pF	$V_{GS}=0V, V_{DS}=-25V, f=1.0MHz$
Reverse Transfer Capacitance	Crss	ALL	[ _	-	400	pF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	-	-	30	ns	
Rise Time	tr	ALL	-	-	15	ns	$V_{DD}=0.5BV_{DSS}$ , $I_D=-10A$ , $Z_O=4.7\Omega$ , (MOSFET switching times are essentially
Turn-Off Delay Time	t <sub>d(off)</sub>	ALL	-	_	20	ns	independent of operating temperature.)
Fall Time	tı	ALL	-	-	12	ns	·
Total Gate Charge (Gate-Source Plus Gate-Drain)	Qg	ALL	-	-	90	nC	V <sub>GS</sub> =-15V,I <sub>D</sub> =-24A, V <sub>DS</sub> =0.8 Max. Rating (Gate charge is essentially independent
Gate-Source Charge	Q <sub>gs</sub>	ALL	-	-	30	nC	of operating temperature.)
Gate-Drain ("Miller") Charge	Qgd	ALL	-		60	nC	•

ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise specified)

#### THERMAL RESISTANCE

Junction-to-Case	RthJC	ALL	_	-	1.0	K/W	
Case-to-Sink	RthCS	ALL	-	0.1		κ/w	Mounting surface flat, smooth, and greased
Junction-to-Ambient		IRFPXXXX IRF95XX	` —`	-	80	к/w	Free Air Operation
	RthJA	IRF91XX	-	- 1	30	K/W	

Notes: (1) TJ=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature

# SAMSUNG SEMICONDUCTOR

#### 7964142 SAMSUNG SEMICONDUCTOR INC IRF9140/9141/9142/9143 IRFP9140/9141/9142/9143 IRF9540/9541/9542/9543

#### **P-CHANNEL POWER MOSFETS**

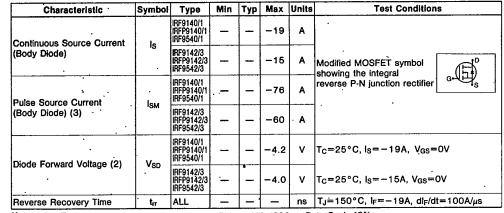
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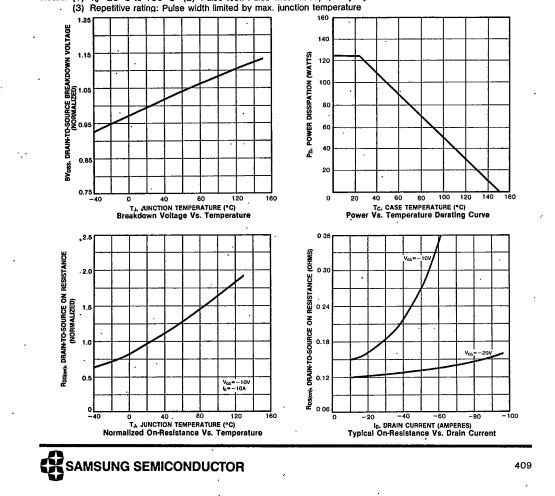
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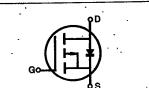
Notes: (1) TJ=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2%



### IRF9230/9231/9232/9233 IRFP9230/9231/9232/9233 IRF9630/9631/9632/9633

**Preliminary Specifications** 

#### - 200 Volt, 0.8 Öhm SFET



### 7964142 SAMSUNG SEMICONDUCTOR INC

### FEATURES • Low RDS(on)

- Improved inductive ruggedness
- Fast switching times ٠
- Rugged polysilicon gate cell structure
- Low Input capacitance
- Extended safe operating area
  Improved high temperature reliability

#### **PRODUCT SUMMARY**

DE

Part Number	VDS	R <sub>DS(on)</sub>	lo
IRF/IRFP9230, IRF9630	0 -200V	0.80	-6.5A
IRF/IRFP9231, IRF963;	1 -150V	០.៩ំព	-6.5A
IRF/IRFP9232, IRF963	2 –200V	1.20	-5.5A
IRF/IRFP9233, IRF963	3 –150V	1.28	-5.5A
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**POWER MOSFETS** 

T-39-21

#### PACKAGE STYLE

Package Type	Part Number
TO-3	IRF9230/9231/9232/9233
то-зр	IRFP9230/9231/9232/9233
TO-220	IRF9630/9631/9632/9633

#### MAXIMUM RATINGS

Characteristic	Symbol	9230 9630	9231 9631	9232 9632	9233 9633	Unit
Drain-Source Voltage (1)	VDSS	-200	-150	-200	-150	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0MΩ) (1)	VDGR	-200	-150	-200	150	Vdc
Gate-Source Voltage	V <sub>GS</sub>		±	20 '		Vdc
Continuous Drain Current Tc=25°C	lo	-6.5	-6.5	-5.5	-5.5	Adc
Continuous Drain Current T <sub>C</sub> =100°C	lo	-4.0	-4.0	-3.5	-3.5	Adc
Drain Current—Pulsed (3)	Ірм	-26	-26	-22	-22	Adc
Gate Current-Pulsed	Ідм	. ±1.5		Adc		
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	PD	75 0.6				Watts W/°C
Operating and Storage Junction Temperature Rangy	T <sub>J</sub> , Tstg	-55 to 150				°G
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL		3	00		°C

Notes: (1) TJ=25°C to 150°C

(2) Pulse test: Pulse width<300µs, Duty Cycle<2%</li>
 (3) Repetitive rating: Pulse width limited by max. junction temperature

### SAMSUNG SEMICONDUCTOR

# IRF9230/9231/9232/9233 IRFP9230/9231/9232/9233 POWER MOSFETS

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ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise specified)

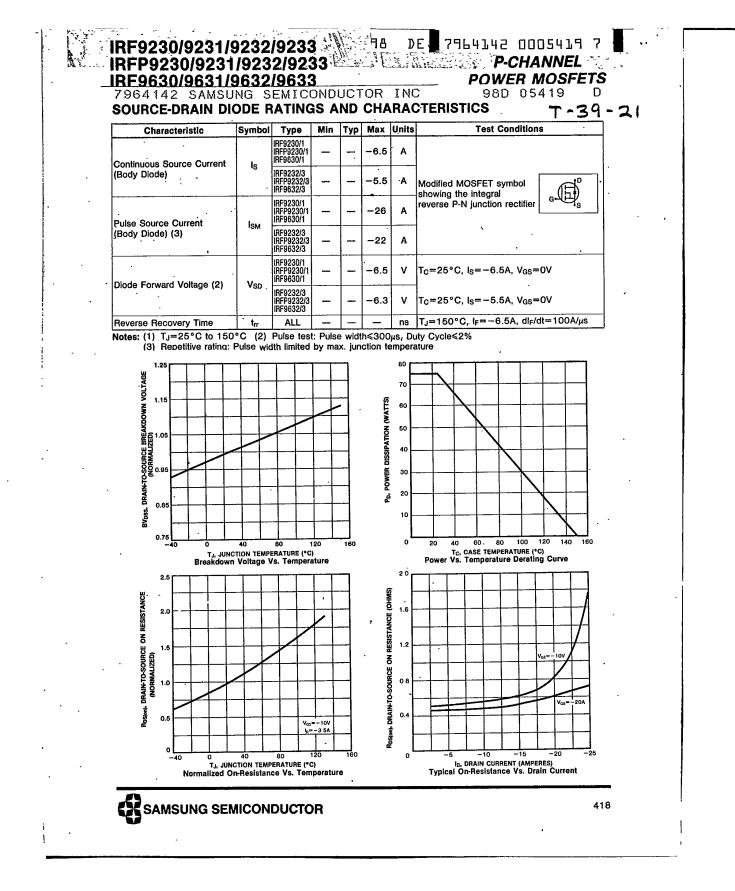
Characteristic	Symbol	Туре	Min	Тур	Max	Units	Test Conditions
Drain-Source Breakdown	BVpss	IRF9230/2 IRF99230/2 IRF9630/2	-200	-	-	v <sup>.</sup>	V <sub>GS</sub> =0V
Voltage	54055	RF9231/3 RFP9231/3 RF9631/3	-150	_	· -	v	i <sub>D</sub> =-250μA
Gate Threshold Voltage	VGS(th)	ALL	-2.0	-	-4.0	V	$V_{DS} = V_{GS}, \ I_{D} = -250 \mu A$
Gate-Source Leakage Forward	lass	ALL	-	-	-100	nA	V <sub>GS</sub> =-20V
Gate-Source Leakage Reverse	loss	ALL		—	100	nA	V <sub>GS</sub> =20V
Zero Gate Voltage	loss	ALL	-	-	-250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
Drain Current	USS.	~~~	1	-	-1000	μA	$V_{DS}$ =Max. Rating×0.8, $V_{GS}$ =0V, $T_C$ =125°C
On-State Drain-Source	la contra	IRF9230/1 IRF99230/1 IRF9630/1	-6.5		_	A	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on)</sub> <sub>max.</sub> , V <sub>GS</sub> ≕−10V
Current (2)	ID(on)	IRF9232/3 IRF99232/3 IRF9632/3	-5.5	-	-	. <b>A</b>	
Static Drain-Source On-State		IRF9230/1 IRF99230/1 IRF9630/1	-	-	0.8	Ω	Vos≃−10V. lo=−3.5A
Resistance (2)	R <sub>DS(on)</sub>	IRF9232/3 IRFP9232/3 IRF9632/3	-	-	1.2	Ω	4
Forward Transconductance (2)	Qís	ALL	2.2	-	-	8	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on)</sub> max., I <sub>D</sub> =-3.5A
Input Capacitance	Cisș	ALL	-	-	650	pF	J
Output Capacitance	Coss	ALL	-	-	300	pF	$V_{GS}=0V, V_{DS}=-25V, f=1.0MHz$
Reverse Transfer Capacitance	Crss	ALL	-	-	90	pF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	-	-	50	ns	
Rise Time	tr	ALL	-	-	100	' ns'	V <sub>DD</sub> =0.5BV <sub>DSS</sub> , I <sub>D</sub> =-3.5A, Z <sub>O</sub> =50 <b>Ω</b> , (MOSFET switching times are essentially
Turn-Off Delay Time	td(off)	ALL	-	-	100	ns	independent of operating temperature.)
Fall Time	· t <sub>f</sub>	ALL	-	-	80	ns	
Total Gate Charge (Gate-Source Plus Gate-Drain	Qg	ALL	-	-	45	nC	V <sub>GS</sub> =-15V, I <sub>D</sub> =-8.0A, V <sub>DS</sub> =0.8 Max. Rating (Gate charge is essentially independen
Gate-Source Charge	Qgs	ALL	-	-	20	nC	d of operating temperature.)
Gate-Drain ("Miller") Charge	Qgd	ALL	-	-	25	nC	

#### THERMAL RESISTANCE

Junction-to-Case	Rthuc	ALL	—		1.67	K/W	
Case-to-Sink	RthCS	ALL	-	1.0	· `	K/W	Mounting surface flat, smooth, and greased
Junction-to-Amblent	BthJA	IRFPXXXX IRF96XX	_	-	80	K/W	Free Air Operation
		IRF92XX	_		30	K/W	

Notes: (1) TJ=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature

SAMSUNG SEMICONDUCTOR



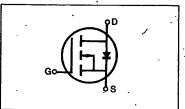
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#### IRF9240/9241/9242/9243 IRFP9240/9241/9242/9243<sup>11</sup> IRF9640/9641/9642/9643

7964142 SAMSUNG SEMICONDUCTOR INC

**Preliminary Specifications** 

#### - 200 Volt, 0.5 Ohm SFET



#### **FEATURES**

- . Low RDS(on)
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Low Input capacitance
- Extended safe operating area
- Improved high temperature reliability

### POWER MOSFETS

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#### **PRODUCT SUMMARY**

Part Number	VDS	R <sub>DS(on)</sub>	lD
IRF/IRFP9240, IRF9640	-200V	0.5 <b>Ω</b>	-11A
IRF/IRFP9241, IRF9641	-150V	0.5 <b>û</b>	-11A
IRF/IRFP9242, IRF9642	-200V	0.7 <b>Ω</b>	-9.0A
IRF/IRFP9243, IRF9643	-150V	0.7 1	-9.0A

#### PACKAGE STYLE

Package Type	Part Number
то-з	IRF9240/9241/9242/9243
<sup>•</sup> то-зр	IRFP9240/9241/9242/9243
TO-220	IRF9640/9641/9642/9643

#### **MAXIMUM RATINGS**

· ·						
Characteristic	Symbol	9240 9640	9241 9641	9242 9642	9243 9643	Unit
Drain-Source Voltage (1)	VDSS	-200	-150	-200	-150	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0MΩ) (1)	VDGR	-200	-150	-200	-150	vac
Gate-Source Voltage	V <sub>GS</sub>		±	20	•	Vdc
Continuous Drain Current Tc=25°C	ĺD	-11	-11	-9.0	-9.0	Adc
Continuous Drain Current Tc=100°C	lo	-7.0	-7.0	-6.0	-6.0	Adc
Drain Current—Pulsed (3)	Ірм	-44	-44	. −36	-36	Adc
Gate Current—Pulsed	IGM ±1.5				Adc	
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	P <sub>D</sub> .	125 · 1.0				Watts W/°C
Operating and Storage Junction Temperature Rangy	T <sub>J</sub> , Tstg <sub>.</sub>	-55 to 150			°C	
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	ΤL	300 ' .				°C

Notes: (1) TJ=25°C to 150°C

(1) 13-25° to 130° C
(2) Pulse test: Pulse width≤300µs, Duty Cycle≤2%
(3) Repetitive rating: Pµlse width limited by max. junction temperature



# 964142 SAMSUNG SEMICONDUCTOR INC IRF9640/9641/9642/9643

#### P-CHANNEL **POWER MOSFETS** T-39-83

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ELECTRICAL	OULADA OTEDIOTION	
ELECINICAL	CHARACTERISTICS	(Tc=25°C unless otherwise specified)

Characteristic	Symbol	Туре	Min	Тур	Max	Unite	Test Conditions	
Drain-Source Breakdown	BVDSS	IRF9240/2 IRF99240/2 IRF9640/2		-	-	v	V <sub>GS</sub> =0V	
Voltage	01033	IRF9241/3 IRF99241/3 IRF9641/3	-150	_	-	v	I <sub>D</sub> =-250μA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$	
Gate-Source Leakage Forward	lass	ALL	_	-	100	nA	V <sub>GS</sub> =-20V	
Gate-Source Leakage Reverse	lgss	ALL	-	ł	100	nA	V <sub>GS</sub> =20V	
Zero Gate Voltage	IDSS	ALL	1	1	-250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =OV	
Drain Current			<u> </u>	_	-1000	μA	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C	
On-State Drain-Source	I <sub>D(on)</sub>	IRF9240/1 IRF99240/1 IRF9640/1	-11		_	A	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , V <sub>GS</sub> =-10V	
Current (2)		IRF9642 IRF9643	-9.0		·	A	ענייאט(on) max., VGS 10V	
Static Drain-Source On-State	R <sub>DS(on)</sub>	IRF9240/1 IRF99240/1 IRF9640/1	-	-	0.5	Ω		
Resistance (2)		IRF9242/3 IRF99242/3 IRF9642/3	-	-	0.7	Ω	$V_{GS} = -10V, I_D = -6.0A$	
Forward Transconductance (2)	9fs	ALL	4.0	-	· _	8	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on)</sub> max., I <sub>D</sub> =-6.0A	
Input Capacitance	Ciss	ALL			1300	pF		
Output Capacitance	Coss	ALL	_	-	450	рF	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, f=1.0MHz	
Reverse Transfer Capacitance	Crss	ALL		-	250	pF		
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	-	_	30	ns		
Rise Time	tr İ	ALL	-		15	ns	$V_{DD} = 0.5BV_{DSS}, I_D = -6.0A, Z_O = 4.7 \Omega,$	
Furn-Off Delay Time	t <sub>d(off)</sub>	ALL	-	-	18		(MOSFET switching times are essentially independent of operating temperature.)	
Fall Time	tr	ALL	-	-	12	ns	independent of operating temperature.)	
Total Gate Charge Gate-Source Plus Gate-Drain)	Q <sub>9</sub> .	ALL	-	-	90	nC	V <sub>GS</sub> =−15V, I <sub>D</sub> =−22A, V <sub>DS</sub> =0.8 Max.	
Gate-Source Charge	Qgs	ALL	-	-	30	-0	Rating (Gate charge is essentially independent	
Bate-Drain ("Miller") Charge	Qgd	ALL	-		60	nC	of operating temperature.)	

#### THERMAL RESISTANCE

Junction-to-Case	RthJC	ALL	_	-	1.0	K/W	
Case-to-Sink	RthCS	ALL -		1.0	_	K/Ŵ	Mounting surface flat, smooth, and greased
Junction-to-Ambient	Rinja	IRFPXXXX IRF96XX	-	-	80		Free Air Operation
	TINJA	IRF92XX		—	.30	κ/w	

Notes: (1) TJ=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature

### SAMSUNG SEMICONDUCTOR

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